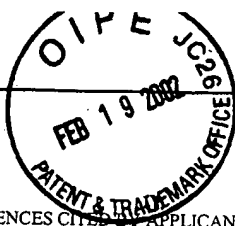


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Kocur et al.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	US 5,650,375 (equivalent of EP 0713646)	7/22/97	Hacker et al			
	AB	US 5,573,998 (equivalent of EP 0514768)	11/12/96	Frisch et al			
	AC	US 5,602,177 (equivalent of EP 0 498 332)	2/11/97	Heinrich et al			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AD	JP 10-287503	10/27/98	Japan				
	AE	JP 10-279406	10/20/98	Japan				
	AF	WO 98/33383	8/6/98	PCT				
	AG	EP 0649649 (English language equivalent)	4/26/95	Europe				
		DE 1 642 122	7/30/70	Germany				
	AH	WO 00/08926	2/24/2000	PCT				
	AI	CA 2,211,200 (equivalent of WO 96/22692)	1/10/96	Canada				
	AJ	EP 0 875 142 A2	11/4/98	Europe				
	AK	WO 91/00010	1/10/91	PCT				
	AL	WO 96/06526	3/7/96	PCT				
	AM	WO 00/05283	2/3/00	PCT				

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AN	Chemical Abstracts, Vol. 101, No. 19, 1984, S. Varkonda et al, also referred to as XP002176644
	AO	Varkonda et al, Vol. 24, No. 6, 1984, pp. 177-179.
	AP	Chemical Abstracts, Vol. 130, No. 2, 1998, Nabeya et al, also referred to as XP 002176645.
	AQ	Database WPI, also referred to as XP 002176646.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>SM</i>	AA	5,428,000	06/27/95	Innami, et al.	504	104	
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
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	AH							
	AI							

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